



# Image analysis methods for cross-contamination detection in raw powders for powder bed fusion

Eleonora Santecchia<sup>1,2</sup>, Paolo Mengucci<sup>2</sup>, Andrea Gatto<sup>3</sup>,  
Elena Bassoli<sup>3</sup>, Lucia Denti<sup>3</sup>, Gianni Barucca<sup>2</sup>

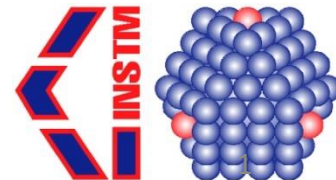
<sup>1</sup>*Consorzio Interuniversitario Nazionale per la Scienza e Tecnologia dei Materiali (INSTM - UdR Ancona), Italy*

<sup>2</sup>*Dipartimento SIMAU, Università Politecnica delle Marche, Via Brezze Bianche 12, 60131 Ancona, Italy*

<sup>3</sup>*Dipartimento DIEF, Università di Modena e Reggio Emilia, Via Vivarelli 10, 41125 Modena, Italy*



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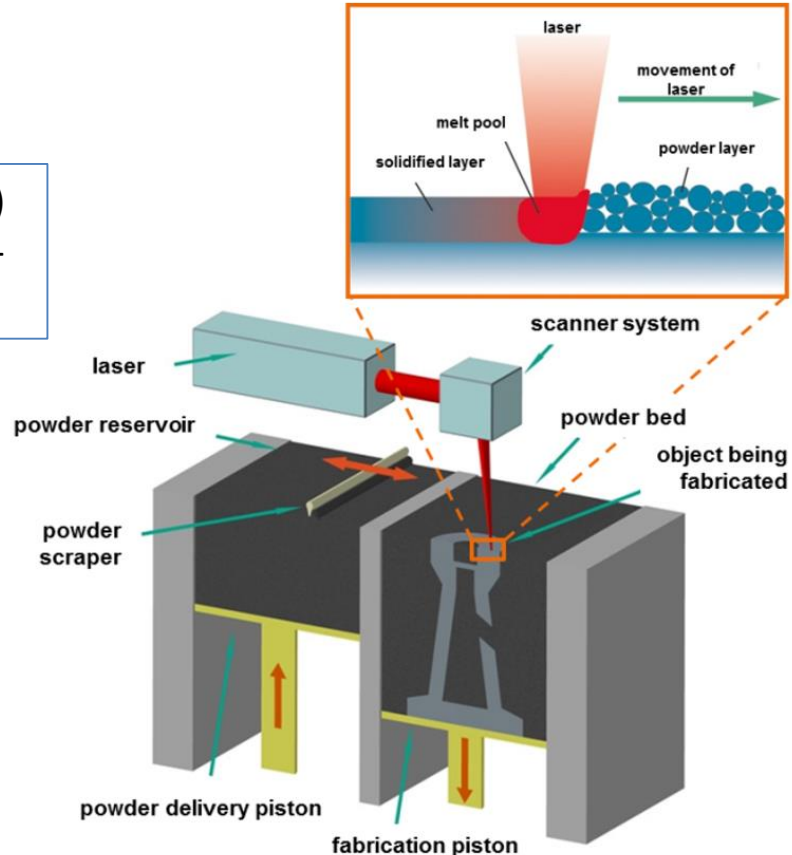
## Powder Bed Fusion (PBF)



The thermal energy (from a **laser** or **electron beam**) selectively **fuses** regions of a **powder bed** in a layer-by-layer fashion, according to a CAD model

## PROBLEMS

- High surface roughness
- Porosity (poor densification)
- Residual thermal stresses
- Heterogeneous microstructure
- Feedstock cross-contamination



Additive Manufacturing 24 (2018) 13–19

Contents lists available at ScienceDirect

Additive Manufacturing

journal homepage: [www.elsevier.com/locate/addma](http://www.elsevier.com/locate/addma)



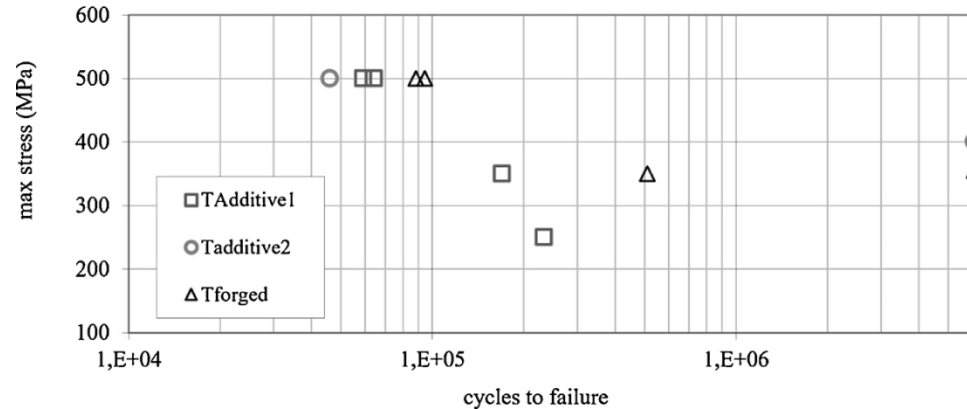
ELSEVIER



Repercussions of powder contamination on the fatigue life of additive manufactured maraging steel

A. Gatto, E. Bassoli, L. Denti\*

AXIAL FATIGUE LIFE  
const. amplitude, R=0



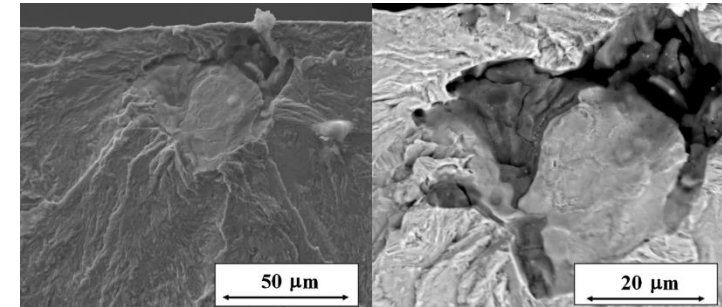
Specimens considered in the experimental plan.

Designation	No. of specimens	Material	Technology	Standard	Age hardening
T <sub>Additive1</sub>	4	18Ni-300	PBF	ASTM E466	6 h at 490 °C
T <sub>Additive2</sub>	2				
T <sub>Forged</sub>	5		FORGING		

Additive1 = powder from lot 1.

Additive2 = powder from lot 2.

SEM

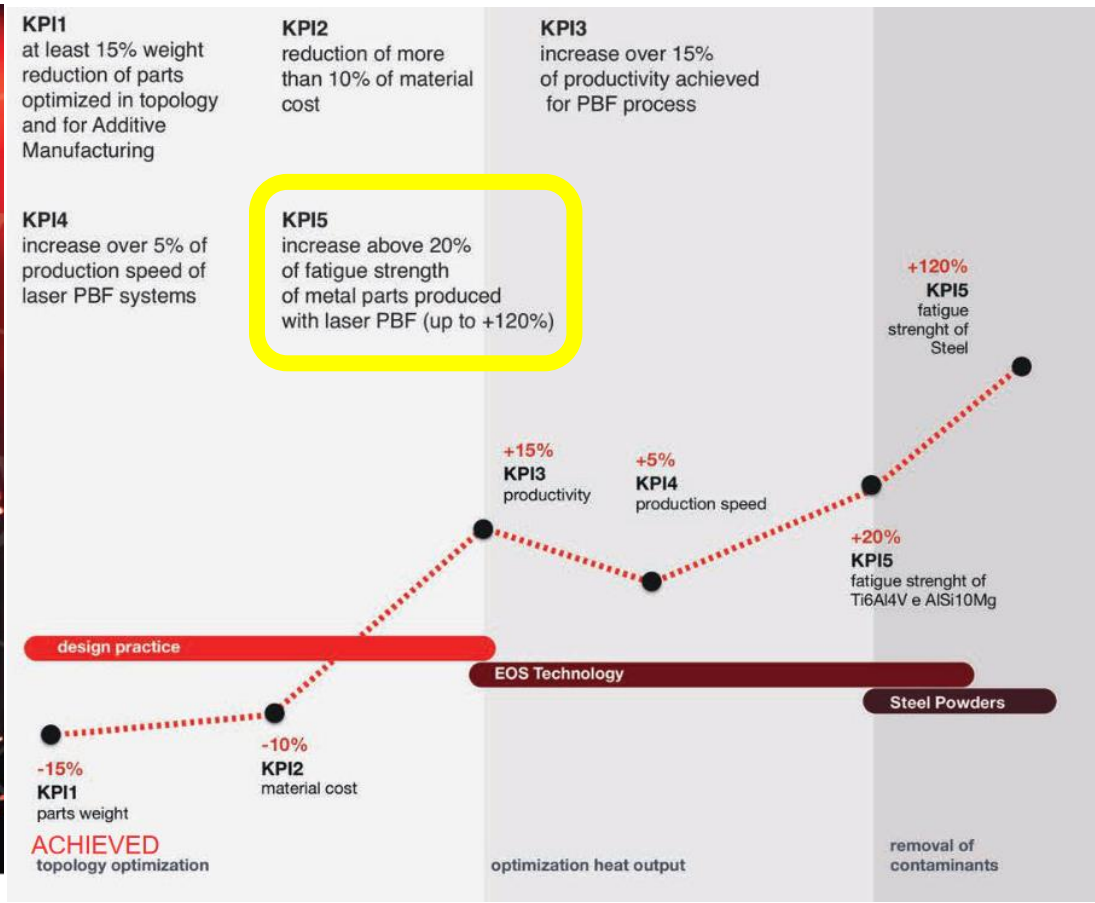


SE

BSE

Ti- and Al-based oxides

# H2020 DREAM Project



## Business Cases

Medium size prosthetic titanium components

Lightweight automotive Aluminum components

Mould Inserts

ADLER ORTHO FRANCE

Ferrari

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EOS Manufacturing solutions

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MIND.4D one step beyond

www.dream-euproject.eu

EUROPEAN UNION

PHOTONICS<sup>21</sup>

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The project has received funding from the European Union's Horizon 2020 research and innovation programme under grant agreement n. 722609

**EURO PM2018**  
CONGRESS & EXHIBITION

## Experimental | Statistical Procedure

**EPMA**  
14 - 18 October 2018  
Bilbao, Spain

1. Put a known quantity of powder on a stub for SEM;
2. **COMPOSITION CHECK** → Acquire a minimum of 3 EDS microanalysis on large areas (200x)
3. **SEM (BSE)-EDS (maps) inspection** → At least 50 fields (500x) of the stub area

Statistical Procedure

Three samples characterized for each condition

4. Count the contaminant particles (n) per inspected area
5. Estimate the total number of contaminant particles (TCP) per stub (stub area=122.6 mm<sup>2</sup>)
6. Estimate the total number of particles per stub (TOT) by the ImageJ analysis software (average TOT=10<sup>5</sup> particles per stub)
7. **Calculate contamination (CC)** from the above quantities (CC=TCP/TOT)

D.C. Montgomery, G.C. Runger, *Applied Statistics and Probability for Engineers*, 6<sup>th</sup> ed., Wiley, 2014, pp. 792  
Eleonora Santeccchia | e.santeccchia@univpm.it



*E. Santeccchia, P. Mengucci, A Gatto, E. Bassoli, L. Denti, F. Bondioli, G. Barucca – EuroPM18 Proceedings*

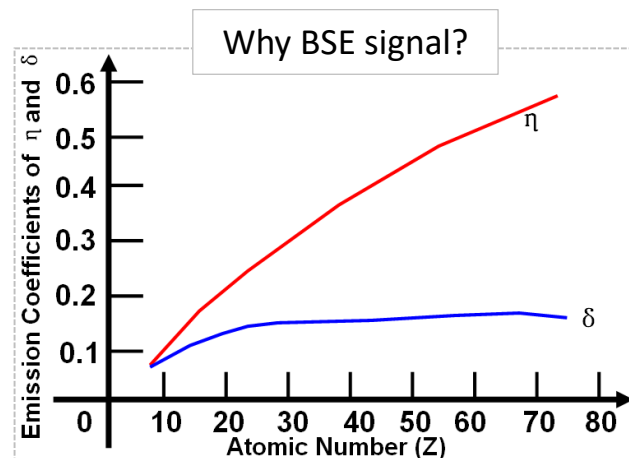
## What is next?

- Faster procedures for cross-contamination estimation (less than 50 micrographs!)
- Automatic detection -> Machine Learning

- ❖ **Scanning Electron Microscopy (SEM)**  
Zeiss Supra 40 (Field emission) SE-ET, SE-in lens, BSE
- ❖ **Energy Dispersive Spectroscopy (EDS)**  
Bruker Quantax Z200, quantitative analysis software
- ❖ **X-ray Diffraction**  
Bruker D8 Advanced, Cu- $\alpha$ , Bragg-Brentano geometry
- ❖ **ImageJ Software**

## SEM Working Parameters

Detector	➡	Backscattered Electrons (BSE)
Aperture	➡	60 $\mu\text{m}$
Magnitude	➡	500x
Working Distance	➡	8.3 mm
Accelerating Voltage	➡	15 keV





## Virgin Powders

- Maraging Steel (EOS MS1\*) → 18% Ni Maraging 300 (US) | 1.2709 (EU)
- Ti6Al4V (EOS Titanium Ti64\*) → ISO 5832-3, ASTM F1472, and ASTM B348

## Contaminated Samples

Sample	Virgin Powder	Controlled Contamination	
		Type	Quantity [wt.%]
MS+0.5Ti64	MS1	Ti64	0.5
MS+1Ti64	MS1	Ti64	1
Ti64+0.5MS	Ti64	MS	0.5
Ti64+1MS	Ti64	MS	1

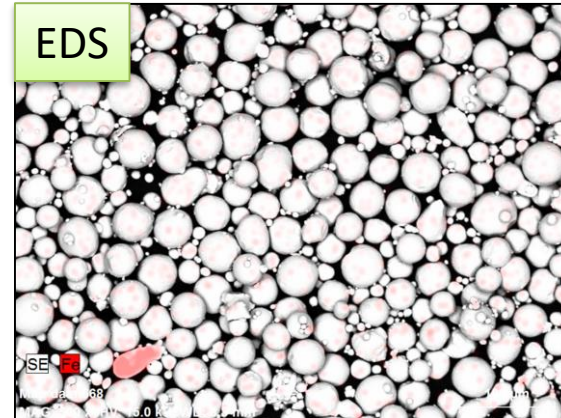
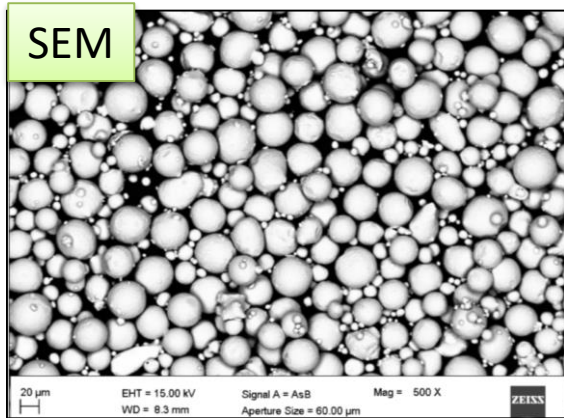
\*EOS GmbH Electro Optical Systems ([www.eos.info](http://www.eos.info)) Contaminated batch: 5 g

### Density (EOS Datasheet)

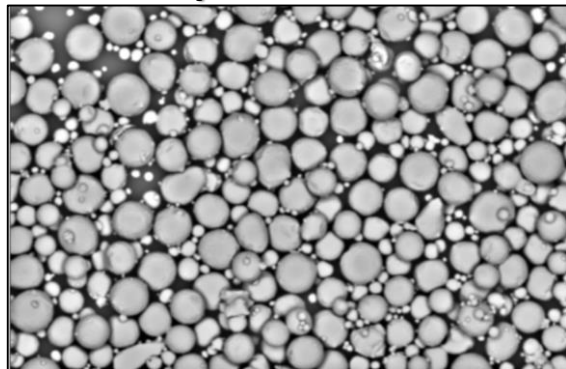
MS1 → 8.0-8.1 g/cm<sup>3</sup>

Ti64 → 4.41 g/cm<sup>3</sup>

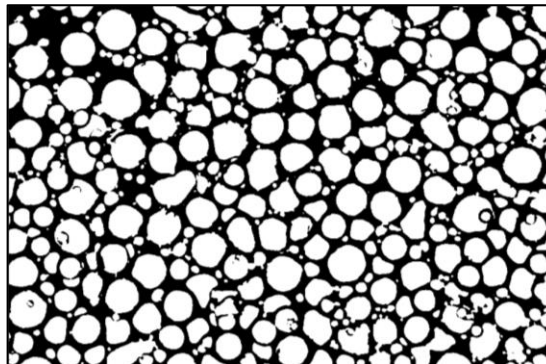
3 Powder samples analyzed for each condition  
5 Micrographs used to quantify the contamination



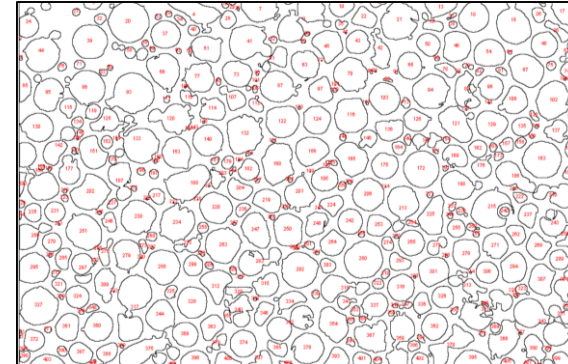
## FFT Bandpass Filter



## Threshold



## Analyze Particles





## Contrast Ratio

### «Analyze Particles»

Area occupied by the particles  
(virgin and contaminants)



EDS elemental map

## Weight Ratio

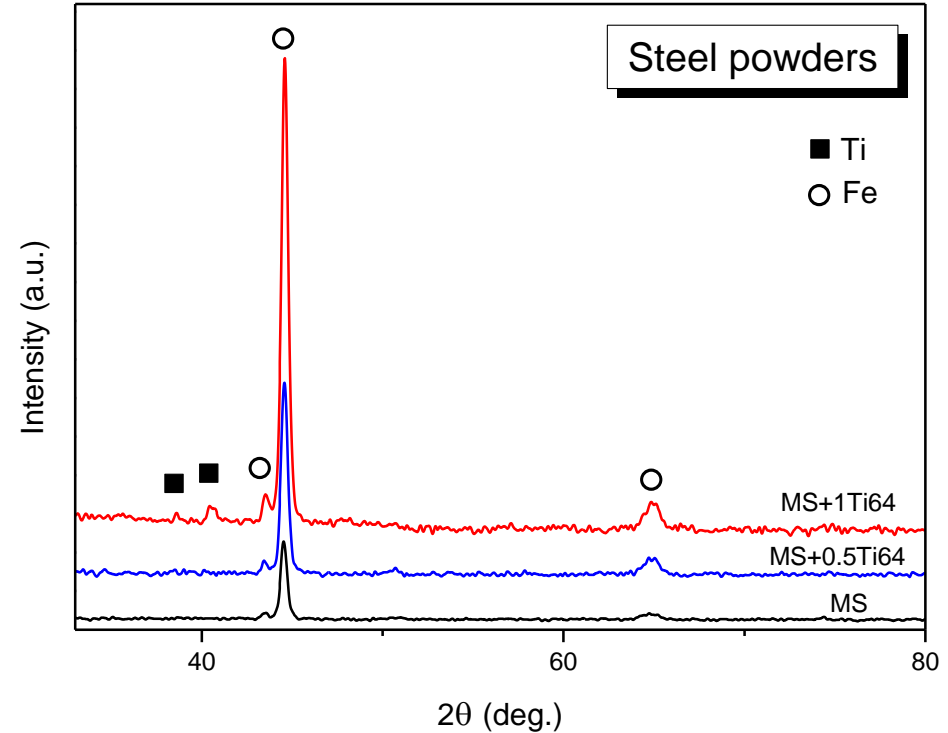
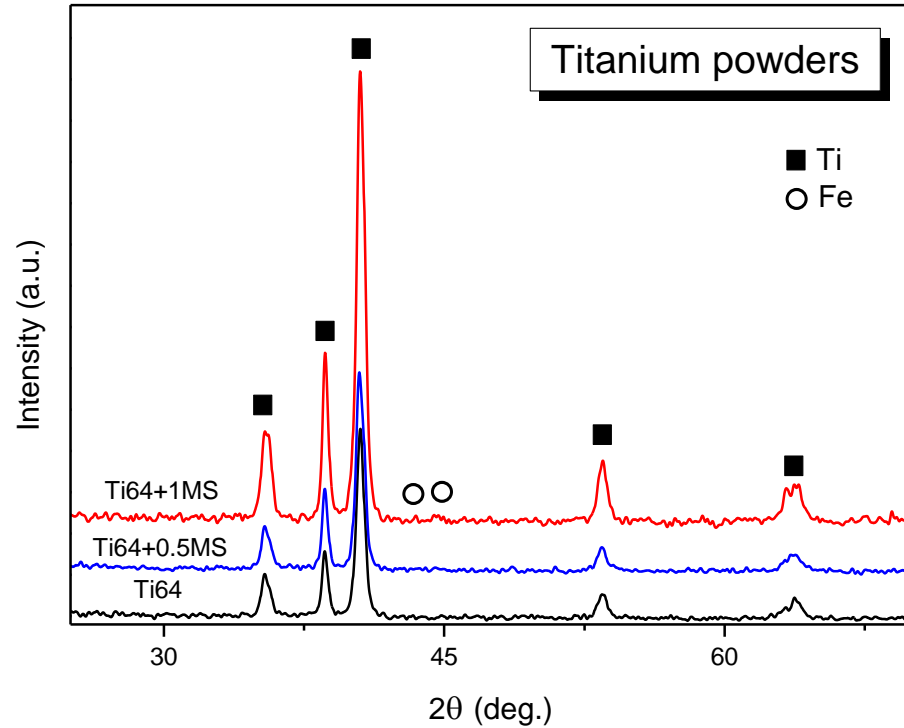
### «Analyze Particles»

Radius of each particle in the  
micrograph → Volume



EDS elemental map

**Hypothesis:** Sphericity of contaminants



**Cross-contamination detected in the MS+1Ti64 sample only!**

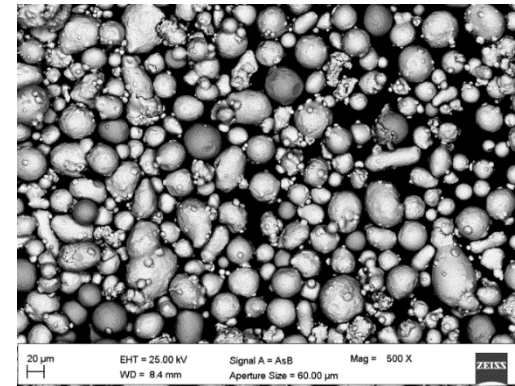
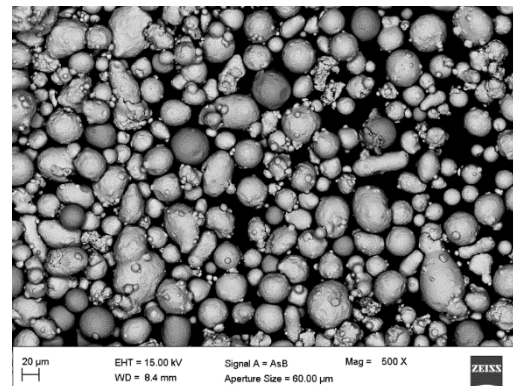
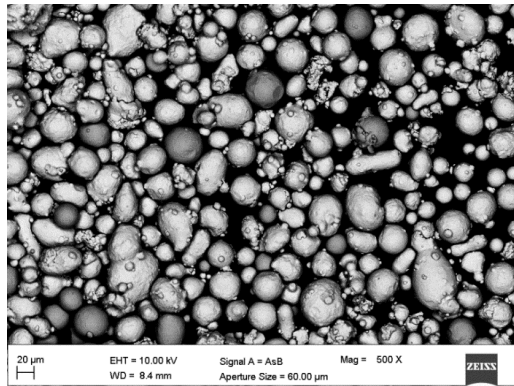
# Results | SEM KeV Selection

10 keV

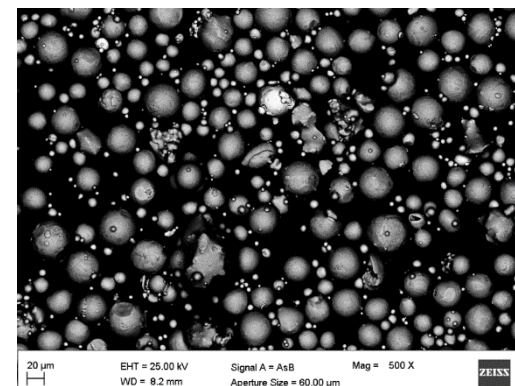
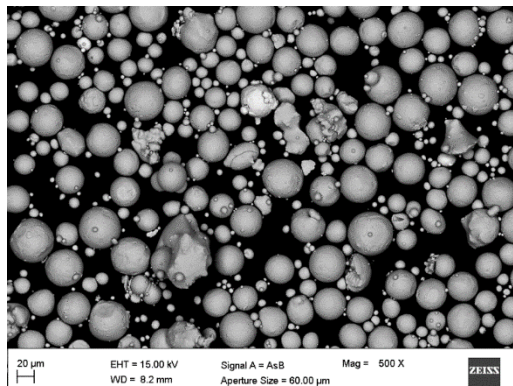
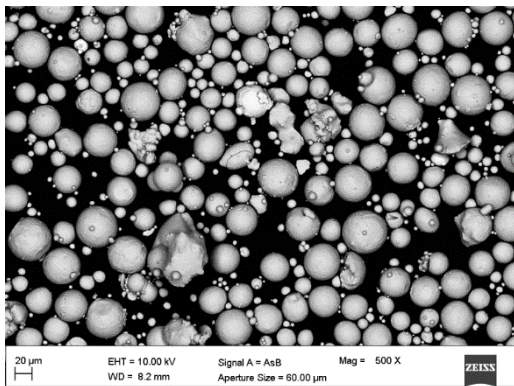
15 keV

25 keV

MS+1Ti64



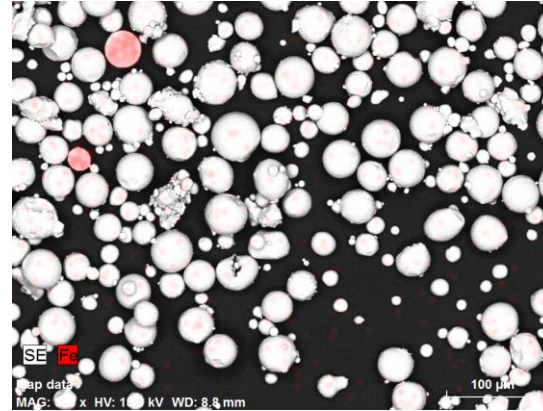
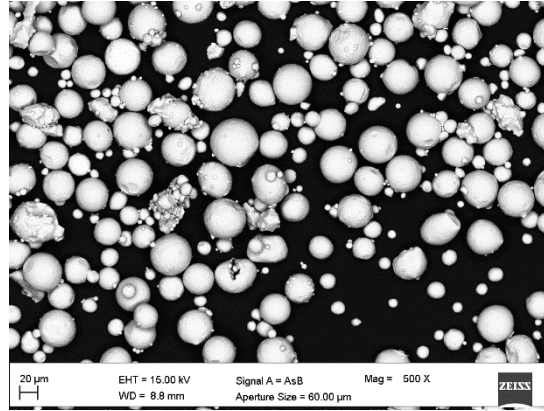
Ti64+1MS



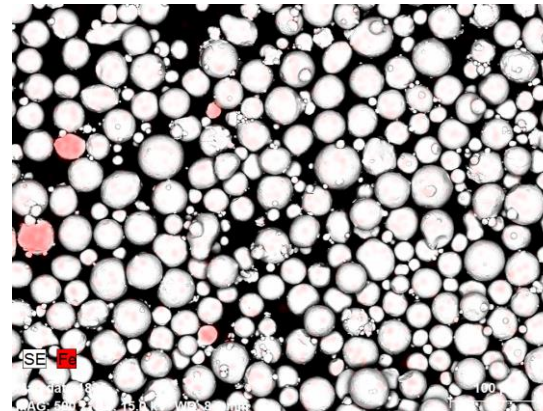
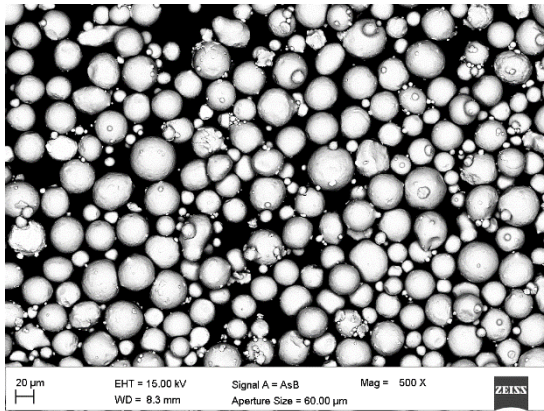


# Results | Ti64 virgin powder

**Ti64+0.5MS**

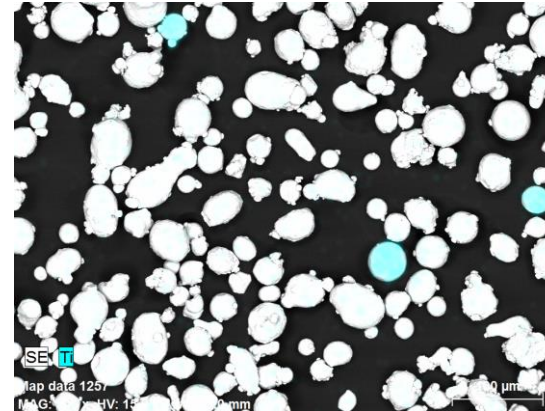
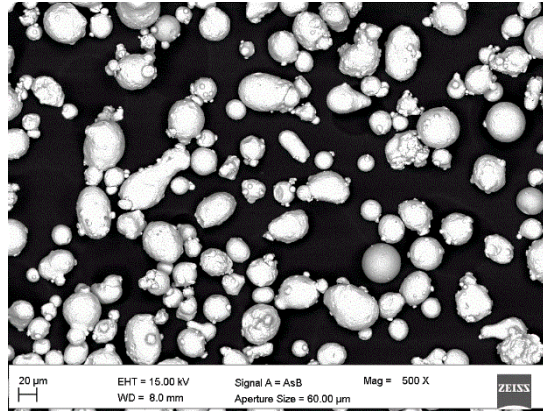


**Ti64+1MS**

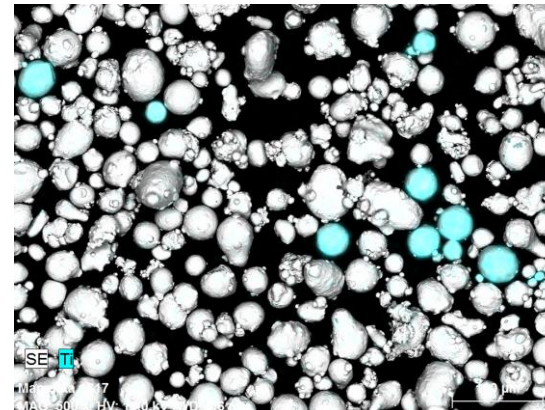
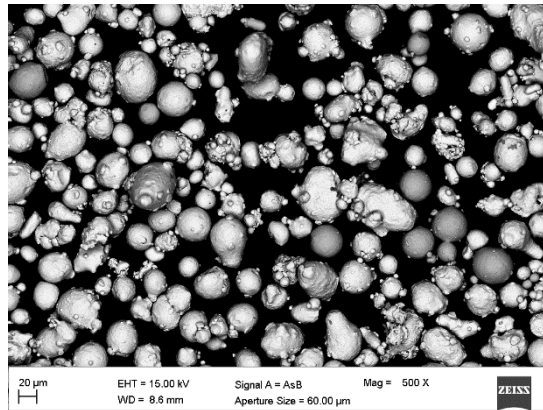


# Results | MS virgin powder

**MS+0.5Ti64**



**MS+1Ti64**





# Results | Cross-Contamination Quantification

Sample Name	Contrast Ratio (%)	Weight Ratio (%)
MS+0.5Ti64	$2.0 \pm 0.2$	$2.5 \pm 0.6$
MS+1Ti64	$3.6 \pm 0.3$	$3.1 \pm 0.8$
Ti64+0.5MS	$1.1 \pm 0.4$	$1.5 \pm 0.6$
Ti64+1MS	$2.0 \pm 0.2$	$3.2 \pm 0.7$



Purely  
phenomenological



Linked with the physical  
properties of the powders

Coherence with the level of introduced contamination!

# Conclusions

- Cross-contamination is hardly detectable by conventional XRD equipment
- The weight ratio procedure overestimates cross-contamination amounts
- Results of the contrast ratio procedure are in good agreement with the ratio of introduced cross-contamination amounts
- By tuning the SEM parameters it is possible to optimize the information of the micrographs for machine learning

# Acknowledgements



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- *P. Mengucci*
- *G. Barucca*
- *A. Di Cristoforo*
- *L. Gobbi*



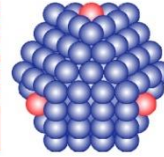
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UNIVERSITÀ DEGLI STUDI DI  
MODENA E REGGIO EMILIA

- *A. Gatto*
- *E. Bassoli*
- *L. Denti*



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- *F. Bondioli*



HORIZON 2020



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# DREAM

# RAM

Research on Additive  
Manufacturing